Docket No.

242749US2

# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Yukio TANIGUCHI

SERIAL NO:

New Application

GAU:

FILED:

Herewith

**EXAMINER:** 

FOR:

CRYSTALLIZATION APPARATUS, CRYSTALLIZATION METHOD, AND PHASE SHIFT MASK AND

FILTER FOR USE IN THESE APPARATUS AND METHOD

## INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

#### REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check is attached in the amount required under 37 CFR §1.17(p).

#### RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

#### CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

#### DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment form is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Marvin J. Spivak

Registration No. 24,913

C. Irvin McClelland Registration Number 21,124

Customer Number

22850

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PHASE SHIFT MASK AND FILTER FOR USE IN THESE APPARATUS AND

**METHOD** 

## STATEMENT OF RELEVANCY

### Reference AW on Form PTO-1449:

This document is disclosed in the body of the specification.

Form PTO 1449 (Modified)			OF COMMERCE EMARK OFFICE	ATTY DOCKET NO.		SERIAL NO.		
			242749US2	New Application				
LIST OF	REFE	RENCES CITED BY API	PLICANT	APPLICANT  Video TANICHOLI				
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				FILING DATE		GROUP		
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U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	ASS SUB FILING DATE IF APPROPRIATE		
	AA							
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	AC							
	AD							
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANS YES		LATION NO
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	AP			-				
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	AS							
	ΑT							
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	ΑV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW	Masakiyo MATSUMURA, "Preparation of Ultra-Large Grain Silicon Thin-Films by Excimer-Laser", SURFACE SCIENCE, Vol. 21, No. 5, pgs. 278-287, 2000						
	AX							
	AY							
	AZ			Additional References sheet(s) attached				
Examiner				D-7/10-1-1-1-1-1-1-1-1-1-1-1-1-1-1-1-1-1-1-		Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in								
conformance	and no	t considered. Include co	ppy of this form	with next communication to applicant.		J.		